

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.
36290/US/2 – 475387-00017

Serial No.
10/501,268

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)

Applicant(s)
Johannes F. de Boer et al.

Filing Date
July 9, 2004

Confirmation No.
7475

U.S. PATENT DOCUMENTS

*Exam. Init.		Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	2004	0	1	0	0	6	8	1	May 2004	Bjarklev et al. ^Φ			
	2004	0	0	8	6	2	4	5	May 2004	Farroni et al. ^Φ			
	2002	0	1	7	2	4	8	5	November 2002	Keaton et al. ^Φ			
	2002	0	1	8	8	2	0	4	December 12, 2002	McNamara et al. ^{ΦΦ}			
	2002	0	0	7	6	1	5	2	June 20, 2002	Hughes et al. ^{ΦΦΦ}			
		6	7	9	0	1	7	5	September 14, 2004	Furusawa et al. ^{ΦΦΦΦ}			
		6	2	6	4	6	1	0	July 24, 2001	Zhu ^{ΦΦΦΦΦ}			
		6	0	1	4	2	1	4	January 11, 2000	Li ^{ΦΦΦΦΦΦ}			
		3	6	0	1	4	8	0	August 24, 1971	Donald Sexton Randall ^{ΦΦΦΦΦΦΦ}			
		5	4	1	1	0	1	6	May 2, 1995	Kume et al. ^{€€}			
		5	7	4	0	8	0	8	April 21, 1998	Panescu et al. ^{€€}			

FOREIGN PATENT DOCUMENT

		Document No.							Date	Country	Class	SubClass	Translator Yes No	
	2005	0	0	0	0	1	1	5	January 6, 2005	WIPO ^{ΦΦ}				
		9	8	0	1	0	7	4	January 15, 1998	WIPO ^{ΦΦ}				
	2004	0	0	6	6	8	2	4	August 12, 2004	WIPO ^{ΦΦ}				
	1	0	3	5	1	3	1	9	June 16, 2005	Germany ^{ΦΦΦΦ}				
		9	8	3	8	9	0	7	September 11, 1998	WIPO ^{ΦΦΦΦ}				
		1	2	5	7	7	7	8	December 22, 1971	Great Britain ^{ΦΦΦΦΦΦΦ}				
	200	5	0	5	4	7	8	0	June 16, 2005	WIPO ^{ΦΦΦΦΦΦΦΦ}				

Examiner

Date Considered

* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	200	6	1	3	0	7	9	7	December 7, 2006	WIPO ^{ΦΦΦΦΦΦΦΦ}				
	200	6	0	1	4	3	9	2	February 9, 2006	WIPO ^{ΦΦΦΦΦΦΦΦ}				
		9	8	4	6	1	2	3	October 22, 1998	WIPO €€				
		0	5	9	0	2	6	8	April 6, 1994	European €€				

^Φ References cited in Office Action dated February 2, 2007 for U.S. Patent Application No. 11/174,425

^{ΦΦ} References cited in International Search Report PCT/US2006/031905

^{ΦΦΦ} References cited in Office Action dated March 28, 2007 for U.S. Patent Application No. 11/241,907

^{ΦΦΦΦ} References cited in International Search Report PCT/US2007/060481

^{ΦΦΦΦΦ} References cited in Office Action dated May 23, 2007 for U.S. Patent Application No. 10/406,751

^{ΦΦΦΦΦΦ} References cited in Office Action dated May 23, 2007 for U.S. Patent Application No. 10/551,735

^{ΦΦΦΦΦΦΦ} References cited in International Search Report PCT/US2007/060717

^{ΦΦΦΦΦΦΦΦ} References cited in International Search Report PCT/US2007/060319

€€ References cited in European Patent Office Search Report for Application No. 01991092.6-2305

OTHER DOCUMENTS (including Author, Title Date, Pertinent Pages, Etc.)

		PCT International Search Report and Written Opinion for Application No. PCT/US2006/031905 dated May 3, 2007
		PCT International Search Report and Written Opinion for Application No. PCT/US2007/060481 dated May 23, 2007
		PCT International Search Report and Written Opinion for Application No. PCT/US2007/060717 dated May 24, 2007
		PCT International Search Report and Written Opinion for Application No. PCT/US2007/060319 dated June 6, 2007
		D. Yelin et al., "Three-dimensional imaging using spectral encoding heterodyne interferometry", Optics Letters, July 15, 2005, Vol. 30, No. 14, Pages 1794-1796 ^{ΦΦΦΦΦΦΦΦ}
		Copy of Office Action dated February 2, 2007 for U.S. Patent Application No. 11/174,425
		Copy of Office Action dated March 28, 2007 for U.S. Patent Application No. 11/241,907
		Copy of Office Action dated May 23, 2007 for U.S. Patent Application No. 10/406,751

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			Copy of Office Action dated May 23, 2007 for U.S. Patent Application No. 10/551,735
			European Patent Office Search report for Application No. 01991092.6-2305 dated January 12, 2006

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